## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under | Reexamination | KIM ET AL. | Examiner | Art Unit | Phu Vu | 2871 | Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2002/0135862	09-2002	Dewald, D. Scott	359/298
*	В	US-6,493,149	12-2002	Ouchi, Satoshi	359/634
*	O	US-6,839,095	01-2005	Bierhuizen et al.	349/9
*	D	US-2002/0180933	12-2002	Ito, Yoshitaka	353/20
*	Е	US-2002/0191154	12-2002	Shahzad et al.	353/20
	F	US-			
	O	US-			
	H	US-			
	ı	US-			·
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
·	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	w	
	×	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.